

FC8J33040L Dual N-channel MOSFET

For switching For DC-DC Converter

- Features
- Low drain-source On-state Resistance : RDS(on) typ = 48 m Ω (VGS = 4.5 V)
- High-speed switching : Qg = 2.8 nC
- Halogen-free / RoHS compliant (EU RoHS / UL-94 V-0 / MSL:Level 1 compliant)
- Marking Symbol: 7A

■ Basic Part Number : Dual Nch MOS 33V (Individual)

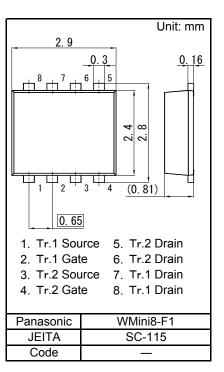
Packaging

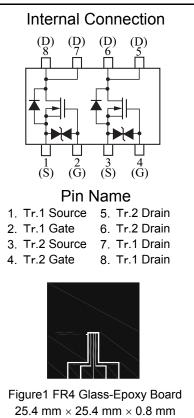
Embossed type (Thermo-compression sealing): 3 000 pcs / reel (standard)

■ Absolute Maximum Ratings Ta = 25 °C Tr.1, Tr.2 Parameter Symbol Rating Unit Drain-source Voltage VDS 33 V Gate-source Voltage VGS ±20 V Drain Current (Steady State) 5 ID 5.5 Drain Current (t = 10 s) IDp 20 Drain Current (Pulsed) А Source Current (Pulsed) ISp 5 (Body Diode) *1,*2 (BD) Total Power Dissipation (Steady State) 1 PD W 1.3 <u>Total Power Dissipati</u>on (t = 10 s) ^{*} Tch 150 °C Channel Temperature Operating Ambient Temperature Topr -40 to + 85 °C Storage Temperature Range Tstg -55 to +150 °C

Note) *1 Device mounted on a glass-epoxy board (See Figure 1)

*2 Pulse test: Ensure that the channel temperature does not exceed 150°C.





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Panasonic

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■ Electrical Characteristics Ta = 25°C ± 3°C Tr.1, Tr.2

Static Characteristics

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source Breakdown Voltage	VDSS	ID = 1 mA, VGS = 0 V	33			V
Zero Gate Voltage Drain Current	IDSS	VDS = 33 V, VGS = 0 V			1	μA
Gate-source Leakage Current	IGSS	VGS = ±16 V, VDS = 0 V			±10	μA
Gate-source Threshold Voltage	Vth	ID = 0.26 mA, VDS = 10 V	1		2.5	V
Drain-source On-state Resistance ^{*1}	RDS(on)1	ID = 2.5 A, VGS = 10 V		32	38	mΩ
	RDS(on)2	ID = 2.5 A, VGS = 4.5 V		48	68	

Dynamic Characteristics

Input Capacitance	Ciss		220	
Output Capacitance	Coss	VDS = 10 V, VGS = 0 V f = 1 MHz	40	pF
Reverse Transfer Capacitance	Crss		35	L
Turn-on Delay Time ^{*2}	td(on)	VDD = 15 V, VGS = 0 to 10 V	7	
Rise Time ^{*2}	tr	ID = 2.5 A	3	ns
Turn-off Delay Time *2	td(off)	VDD = 15 V, VGS = 10 to 0 V	15	115
Fall Time ^{*2}	tf	ID = 2.5 A	9	
Total Gate Charge	Qg	VDD = 15 V, VGS = 0 to 4.5 V,	2.8	
Gate-source Charge	Qgs	VDD = 15 V, VGS = 0.004.5 V, ID = 5 A	1.1	nC
Gate-drain Charge	Qgd		1.2	

Body Diode Characteristic

Diode Forward Voltage *1	VSD	IS = 2.5 A, VGS = 0 V	0.8	1.2	V		
Note) 1 Measuring methods are based on IADANESE INDUSTRIAL STANDARD, US C 7020 Measuring methods for transistore							

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 Measuring methods for transistors.

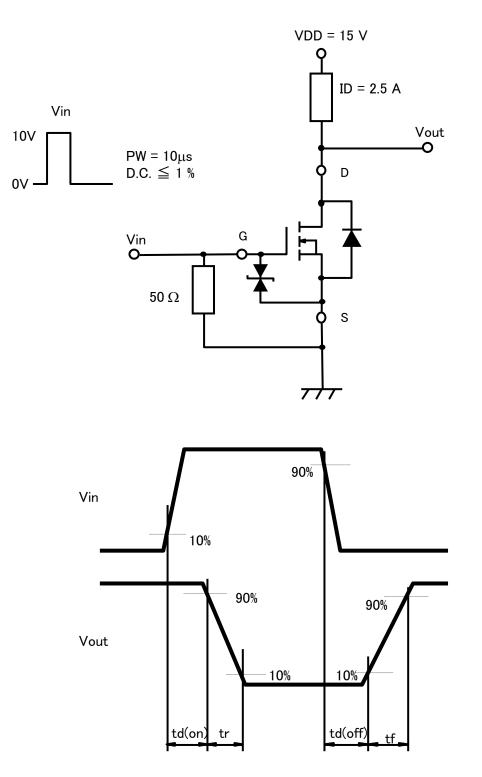
2. *1 Pulse test: Ensure that the channel temperature does not exceed 150°C.

*2 Measurement circuit for Turn-on Delay Time/Rise Time/Turn-off Delay Time/Fall Time

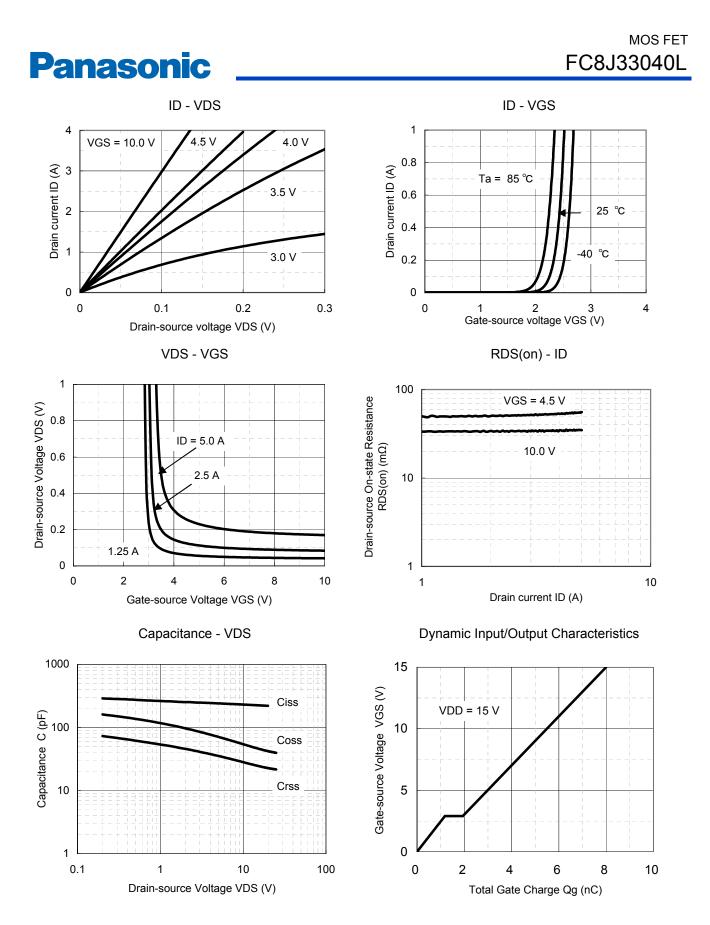
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*2 Measurement circuit for Turn-on Delay Time/Rise Time/Turn-off Delay Time/Fall Time

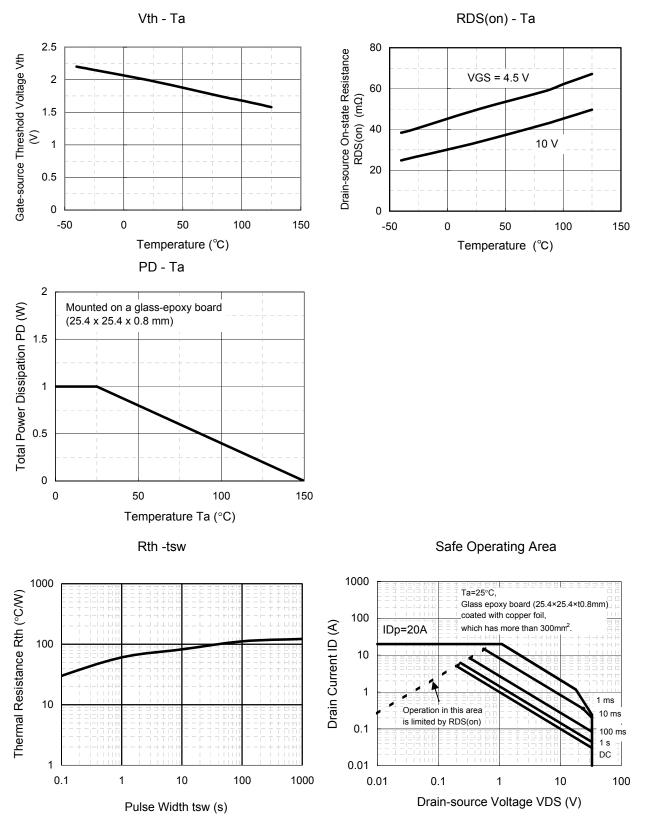


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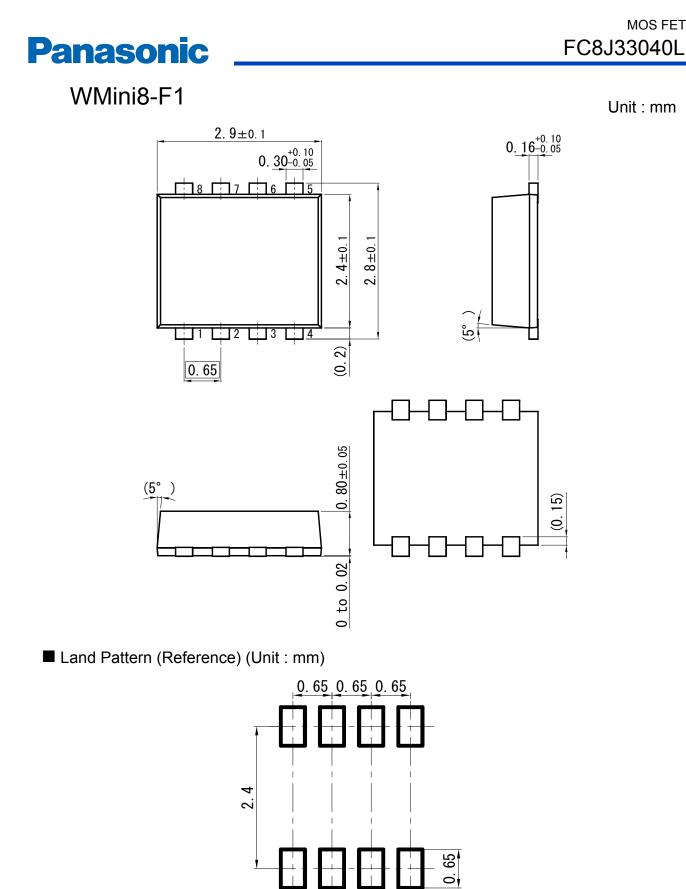




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